

Date	User	Film	Recipe	Chuck T	Coat time	Dep.time	Thickness	JAW EC-400 (Woolam S.E.)			Index	Index+1%	Index -1%	Dep.rate	Avg.dep. rate			HF e.r.	Stress	LPD (light point defects)		Comment
								Index @632.8n	Index @1550	Index @632.8					(nm/min)	(nm/min)	(nm/min)			(nm/min)	(nm/min)	
					300°C	min	sec	(Å)	m	nm	nm				(nm/min)	Mpa						
01/17/14	Biljana	SiO2	Oxide	300	10min	600.00	2855.83	1.472	1.461	1.473	1.488	1.458	28.56	27.99	29.38	26.59	493.56	-281.41	166	329	Uniform film	
01/29/14	Biljana	SiO2	Oxide	300	10min	600.00	2762.42	1.474	1.463	1.473	1.488	1.458	27.62	27.99	29.38	26.59					Uniform film	
02/03/14	Biljana	SiO2	Oxide	300	10min	600.00	2772.81	1.473	1.462	1.473	1.488	1.458	27.73	27.99	29.38	26.59	576.43	-262.42	116	285	Uniform film	
02/13/14	Biljana	SiO2	Oxide	300	10min	975.00	4606.00	1.474	1.463	1.473	1.488	1.458	28.34	27.99	29.38	26.59					1/2 wafer	
02/13/14	Biljana	SiO2	Oxide	300	10min	960.00	4504.00	1.474	1.462	1.473	1.488	1.458	28.15	27.99	29.38	26.59					small piece	
02/18/14	Biljana	SiO2	Oxide	300	10min	600.00	2772.60	1.473	1.462	1.473	1.488	1.458	27.73	27.99	29.38	26.59	574.32	-265.31	29	137	Uniform film	
03/12/14	Biljana	SiO2	Oxide	300	10min	600.00	2776.83	1.473	1.462	1.473	1.488	1.458	27.77	27.99	29.38	26.59	544.14	-283.68	87	115	Uniform film	

Avg Index	1.473	Avg.dep.rate	27.99		547.11	-273.21
Index+1%	1.488	Avg+5%	29.38			
Index-1%	1.458	Avg-5%	26.59			
Stand.dev	0.00	Stand.dev	0.36			
UCL	1.48	UCL	29.08			
LCL	1.47	LCL	26.89			

